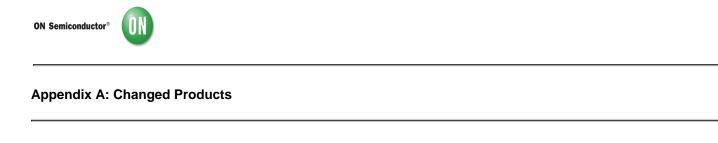


Final Product/Process Change Notification Document #: FPCN22773X

Issue Date: 29 August 2019

Title of Change:	ON Carmona, Philippines new probe location site addition for Part NLHV4157N.			
Proposed first ship date:	23 January 2020			
Contact information:	Contact your local ON Semiconductor Sales Office or <ovidiu.tol@onsemi.com></ovidiu.tol@onsemi.com>			
Samples:	Contact your local ON Semiconductor Sales Office or < PCN.samples@onsemi.com > Sample requests are to be submitted no later than 30 days from the date of first notification, Initial PCN or Final PCN, for this change. Samples delivery timing will be subject to request date, sample quantity and special customer packing/label requirements.			
Additional Reliability Data:	Contact your local ON Semiconductor Sales Office			
Type of notification:	This is a Final Product/Process Change Notification (FPCN) sent to customers. FPCNs are issued 90 days prior to implementation of the change. ON Semiconductor will consider this change accepted, unless an inquiry is made in writing within 30 days of delivery of this notice. To do so, contact < PCN.Support@onsemi.com>			
Change Part Identification:	Date code will identify un	it with this change.		
Change Category:	☐ Wafer Fab Change ☐ Assembly Change ☐ Test Change ☐ Other PROBE			
Change Sub-Category(s): ☐ Manufacturing Site Addition ☐ Manufacturing Site Transfer ☑ Manufacturing Process Change	☐ Material Change ☐ Product specific change ☐ Product specific change ☐ Other: ☐ PROBE			
	ON Semiconductor Sites:		External Foundry/Subcon Sites:	
Sites Affected:	ON Carmona, Philippines		None	
Description and Purpose: ON Semiconductor would like to inform its c	ON Carmona, Philippines	f a sort insertion in the test flow	None	
Description and Purpose:	ON Carmona, Philippines ustomers for the addition of	f a sort insertion in the test flow ge Description	None	
Description and Purpose:	ON Carmona, Philippines ustomers for the addition of		None for NLHV4157.	
Description and Purpose: ON Semiconductor would like to inform its c	ON Carmona, Philippines ustomers for the addition of Before Change N result of this change.	ge Description	for NLHV4157. After Change Description	
Description and Purpose: ON Semiconductor would like to inform its continuous probe Location There are no product material changes as a seminary probe and product material changes as a seminary probability probe to the product material changes as a seminary probability probabilit	ON Carmona, Philippines ustomers for the addition of Before Change N result of this change.	ye Description /A	for NLHV4157. After Change Description ON Carmona, Philippines	
Description and Purpose: ON Semiconductor would like to inform its continuous problems. Probe Location There are no product material changes as a result of the product marking change as a result	ON Carmona, Philippines ustomers for the addition of Before Change N result of this change. ult of this change.	ye Description /A plementation of a sort insertion	for NLHV4157. After Change Description ON Carmona, Philippines	
Description and Purpose: ON Semiconductor would like to inform its continuous problems. Probe Location There are no product material changes as a result of the problems. There is no product marking change as a result of the problems. There is no Reliability Data Summary: There is no Reliability Data Summary:	ON Carmona, Philippines ustomers for the addition of Before Change N result of this change. ult of this change.	ye Description /A plementation of a sort insertion	for NLHV4157. After Change Description ON Carmona, Philippines	
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Description and Purpose: ON Semiconductor would like to inform its continuous problems. Probe Location There are no product material changes as a result of the seminary product marking change as a result of the seminary. There is no Result of the seminary problems of the seminary problems of the seminary problems. It is a seminary problems of the seminary problems of the seminary problems of the seminary problems. Note: Only the standard (off the shelf) part of the seminary problems of	ON Carmona, Philippines ustomers for the addition of Before Change N result of this change. ult of this change. eliability required for the im trical characteristics are not	plementation of a sort insertion impacted.	for NLHV4157. After Change Description ON Carmona, Philippines in the test flow for NLHV4157.	

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Product	Customer Part Number	Qualification Vehicle
NLHV4157NDFT2G		NLHV4157NDFT2G